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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/807,306	03/24/2004	Hiroshi Tanaka	00862.023511	3829
5514 7590 08/24/2006			EXAMINER	
	K CELLA HARPER &	AKANBI, ISIAKA O		
30 ROCKEFELLER PLAZA NEW YORK, NY 10112			ART UNIT	PAPER NUMBER
1,2,, 10141,			2877	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)			
Office Action Summary		10/807,306	TANAKA, HIROSHI			
		Examiner	Art Unit			
		Isiaka O. Akanbi	2877			
Period fo	The MAILING DATE of this communication app or Reply	pears on the cover sheet with the o	correspondence address			
WHIC - External after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPL' CHEVER IS LONGER, FROM THE MAILING D. Insions of time may be available under the provisions of 37 CFR 1.1 SIX (6) MONTHS from the mailing date of this communication. In period for reply is specified above, the maximum statutory period or re to reply within the set or extended period for reply will, by statute reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tir will apply and will expire SIX (6) MONTHS from the cause the application to become ABANDONE	N. nely filed the mailing date of this communication. (D) (35 U.S.C. § 133).			
Status						
1) 又	Responsive to communication(s) filed on 24 M	arch 2004.				
· <u> </u>		action is non-final.				
'=	Since this application is in condition for allowa		osecution as to the merits is			
,	closed in accordance with the practice under E	•				
Dienoeiti	on of Claims	,				
· _						
	Claim(s) 1-16 is/are pending in the application.					
	4a) Of the above claim(s) is/are withdrawn from consideration.					
-	Claim(s) is/are allowed.					
	Claim(s) <u>1-16</u> is/are rejected.					
	•					
8)	Claim(s) are subject to restriction and/o	r election requirement.				
Applicati	on Papers					
9)[	The specification is objected to by the Examine	r.				
10)🖾	0)⊠ The drawing(s) filed on <u>24 March 2004</u> is/are: a)⊠ accepted or b) objected to by the Examiner.					
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
	Replacement drawing sheet(s) including the correct		·			
11)	The oath or declaration is objected to by the Ex		• • • • • • • • • • • • • • • • • • • •			
Priority u	ınder 35 U.S.C. § 119					
_	Acknowledgment is made of a claim for foreign All b) Some * c) None of:  1. Certified copies of the priority documents 2. Certified copies of the priority documents	s have been received.				
	3. Copies of the certified copies of the prior application from the International Bureau	rity documents have been receive u (PCT Rule 17.2(a)).	ed in this National Stage			
* S	see the attached detailed Office action for a list	of the certified copies not receive	ed.			
Attachmen	• •					
	e of References Cited (PTO-892)	4) Interview Summary				
	e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449 or PTO/SB/08)	Paper No(s)/Mail Da				
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  Paper No(s)/Mail Date 12 May 2004.  5) Notice of Informal Patent Application (PTO-152)  6) Other:						

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#### **DETAILED ACTION**

## Information Disclosure Statement

The information disclosure statement file 12 May 2004 has been entered and reference considered by the examiner.

## **Drawings**

The examiner approves the drawings filed 24 March 2004.

## Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claim 3 is rejected under 35 U.S.C. 112, second paragraph, as reciting the limitation " a plurality of the first marks " in line 2. There is insufficient antecedent basis for this limitation in the claim.

### **Double Patenting**

The nonstatutory double patenting rejection is based on a judicially created doctrine grounded in public policy (a policy reflected in the statute) so as to prevent the unjustified or improper timewise extension of the "right to exclude" granted by a patent and to prevent possible harassment by multiple assignees. A nonstatutory obviousness-type double patenting rejection is appropriate where the conflicting claims are not identical, but at least one examined application claim is not patentably distinct from the reference claim(s) because the examined application claim is either anticipated by, or would have been obvious over, the reference claim(s). See, e.g., *In re Berg*, 140 F.3d 1428, 46 USPQ2d 1226 (Fed. Cir. 1998); *In re Goodman*, 11 F.3d 1046, 29 USPQ2d 2010 (Fed. Cir. 1993); *In re Longi*, 759 F.2d 887, 225 USPQ 645 (Fed. Cir. 1985); *In re Van Ornum*, 686 F.2d 937, 214 USPQ 761 (CCPA 1982); *In re Vogel*, 422 F.2d 438, 164 USPQ 619 (CCPA 1970); and *In re Thorington*, 418 F.2d 528, 163 USPQ 644 (CCPA 1969).

A timely filed terminal disclaimer in compliance with 37 CFR 1.321(c) or 1.321(d) may be used to overcome an actual or provisional rejection based on a nonstatutory double patenting ground provided the conflicting application or patent either is shown to be commonly owned with this application, or claims an invention made as a result of activities undertaken within the scope of a joint research agreement.

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Effective January 1, 1994, a registered attorney or agent of record may sign a terminal disclaimer. A terminal disclaimer signed by the assignee must fully comply with 37 CFR 3.73(b).

Claims 1-16 are rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-15 of U.S. Patent No. 6949755. Although the conflicting claims are not identical, they are not patentably distinct from each other because the method claims in Patent 755 also provide the means for apparatus (the means claims of 755 provide the limitation of the 10807306). This is a provisional obviousness-type double patenting rejection because the conflicting claims have not in fact been patented. The claims of the applications correspond to each other as follows:

10/807306	6,949,755	
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14	11	
15	12,13	
16	12,13	

The difference between the present application and the Patent 755 is that the present application claimed a unit which selects a second mark different from the target mark as a new target mark based on the position of the first mark and the feature while the patent 755 claimed a unit which detects a position of target mark based on the position of the first mark and the feature. The patent 755 claimed plurality of marks (i.e. second mark) that would anticipate the claims of the present application.

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The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tanaka (5,249,016).

Claims 1 15 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tanaka. The reference of Tanaka teaches of apparatus/method, which detects a position of a target mark included in an object comprising a unit (CU) which senses an image of the object (WF), a unit (OE) which extracts a first mark (pre-alignment marks)(WAMR/WAML) and feature (WMR/WML) of a region outside of the first mark in the image and a unit (CU) which selects a second mark (WAMR/WAML)(a plurality of marks formed so that a target marks is recognized) and a unit (CM)(col. 2, line 15-65)(col. 3, line 63-col. 5, line 41)(fig. 1), however the reference of Tanaka is silent regarding a second mark different from the target mark as a new target mark based on the position of the first mark and the feature. It would have been obvious to one having ordinary skill in the art at the time of invention to provide a second mark that is different from the target mark as a new target mark based on the position of the first mark and the feature for the purpose of providing alignment precision.

As to claims 2-9, Tanaka discloses everything claimed, as applied to claim 1 above, comprising a plurality of marks (WAMR/WAML) formed so that a target marks is recognized (col. 2, line 15-65)(col. 3, line 63-col. 5, line 41)(figs. 4,5,7 and 9). The reference of Tanaka is silent regarding the feature corresponds to an auxiliary mark. It would have been obvious to one having ordinary skill in the art at the time of invention to provide extracted features that correspond to an auxiliary mark, which is included in the object and associated with the desired marks for the purpose of providing a more accurate alignment.

As to claims 10-12, Tanaka discloses everything claimed, as applied to claim 1 above, in addition Tanaka discloses wherein the object (w) is a substrate on which a device is to be formed, a stage unit (XYS) which positions the substrate and a unit (CU) which controls

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positioning of the substrate by said stage unit based on the position of the target mark (fig. 1)(col. 4, line 11-69)(col. 5, line 9-41).

As to claim 13, Tanaka discloses everything claimed, as applied to claim 1 above, in addition Tanaka discloses wherein the object (W) is a first substrate on which a device is to be formed (fig. 1)(col. 5, line 9-41) and teaches plurality of marks formed so that a target mark is recognized as applied above, It would have been obvious to one having ordinary skill in the art at the time of invention to provide a mark corresponding to the second mark that is initially selected as the target mark with respect to a subsequent substrate in a lot including the first substrate for the purpose of providing a more accurate measurement and alignment.

Claim 14 is rejected under 35 U.S.C. 103(a) as being unpatentable over Tanaka. The reference of Tanaka teaches of apparatus of the features of claim 14, comprising a plurality of marks formed so that a target marks is recognized, a stage unit (XYS) which positions the substrate, a unit (CU) which senses an image of the substrate (W), a unit (OE) which extracts/selects feature of a region, a unit which controls said stage unit (XYS) so as to position the substrate based on the position of the target mark (fig. 1)(col. 4, line 40-67)(col. 2, line 15-65)(col. 3, line 63-col. 5, line 41), however the reference of Tanaka is silent regarding a second mark different from the target mark as a new target mark based on the position of the first mark and the feature. It would have been obvious to one having ordinary skill in the art at the time of invention to provide a second mark that is different from the target mark as a new target mark based on the position of the first mark and the feature for the purpose of providing a more accurate measurement and alignment.

Claim 16 is rejected under 35 U.S.C. 103(a) as being unpatentable over Tanaka. The reference of Tanaka teaches of a method of the features of claim 16, comprising sensing (CU) an image of a substrate, wherein a plurality of marks (WAMR and WAML) included in the object can be included in the image, extracting (OE) feature of a region, however the reference of Tanaka is silent regarding selecting a second mark different from the target mark as a new target mark based on the position of the first mark and the feature and transferring a pattern concerning the device to the substrate based on the position of the target mark. It would have been obvious to one having ordinary skill in the art at the time of invention to provide and select a second mark that is different from the target mark as a new target mark based on the position of the first mark and the feature for the purpose of providing a more accurate measurement and alignment. Additionally, it would have been obvious to one having ordinary skill in the art at the

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time of invention to transfer a pattern concerning the device to the substrate based on the position of the target mark for the purpose of providing a more accurate alignment.

#### **Additional Prior Art**

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. The references listed in the attached form PTO-892 teach of other prior art apparatus/method which detects a position of a target mark included in an object that may anticipate or obviate the claims of the applicant's invention.

#### Conclusion

# Fax/Telephone Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Isiaka Akanbi whose telephone number is (571) 272-8658. The examiner can normally be reached on 8:00 a.m. - 4:30 p.m.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J. Toatley Jr. can be reached on (571) 272-2059. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Isiaka Akanbi

August 10, 2006

Gregory J. Toetley, Jr.